

C²MOS DIGITAL INTEGRATED CIRCUIT SILICON MONOLITHIC

TC40H175P/F

TC40H175 QUAD D-TYPE FLIP-FLOP

The TC40H175 is a quad D-type flip-flop having common CLOCK and common CLEAR input.

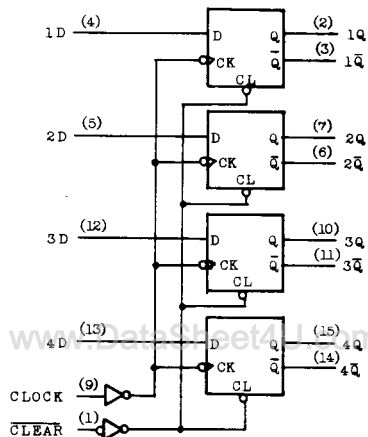
The logical input applied to data input is transmitted to outputs Q and $\bar{Q}$ at the rising edge of CLOCK input.

When CLEAR input is set to "L" level, output Q goes to "L" level and output $\bar{Q}$ to "H" level, respectively.

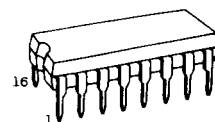
MAXIMUM RATINGS

CHARACTERISTIC	SYMBOL	RATING	UNIT
Supply Voltage	V _{DD}	V _{SS} -0.5 ~ V _{SS} +10	V
Input Voltage	V _{IN}	V _{SS} -0.5 ~ V _{DD} +0.5	V
Output Voltage	V _{OUT}	V _{SS} -0.5 ~ V _{DD} +0.5	V
Input Current	I _{IN}	±10	mA
Power Dissipation	PD	300(DIP)/180(MFP)	mW
Storage Temperature	T _{stg}	-65 ~ 150	°C
Lead Temp./Time	T _{sol}	260°C • 10 sec	

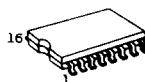
LOGIC DIAGRAM



* ALL INPUTS ARE EQUIPPED WITH PROTECTION CIRCUIT.

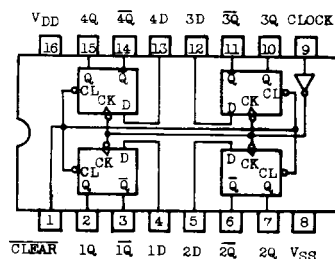


DIP16 (3D16A-P)



MFP16 (F16GC-P)

PIN CONNECTION



TRUTH TABLE

INPUTS			OUTPUTS	
CLEAR	CLOCK	DATA	Q	$\bar{Q}$
L	X	X	L	H
H		H	H	L
H		L	L	H
H		X	No Change	No Change

X = Don't Care

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RECOMMENDED OPERATING CONDITIONS (V_{SS}=0.0V)

CHARACTERISTIC	SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Supply Voltage	V _{DD}	—	2.0	—	8.0	V
Input Voltage	V _{IN}	—	0	—	V _{DD}	V
Operating Temperature	T _{opr}	—	-40	—	85	°C

ELECTRICAL CHARACTERISTICS (V_{SS}=0.0V)

CHARACTERISTIC	SYMBOL	TEST CONDITION	V _{DD} (V)	-40°C		25°C			85°C		UNIT
				MIN.	MAX.	MIN.	TYP.	MAX.	MIN.	MAX.	
High Level Output Voltage	V _{OH}	I _{OUT} < 1μA V _{IN} =V _{SS} , V _{DD}	5	4.95	—	4.95	5.0	—	4.95	—	V
Low Level Output Voltage	V _{OL}	I _{OUT} < 1μA V _{IN} =V _{SS} , V _{DD}	5	—	0.05	—	0.0	0.05	—	0.05	V
High Level Output Current	I _{OH}	V _{OH} =4.6V V _{IN} =V _{SS} , V _{DD}	5	-0.52	—	-0.44	—	—	-0.36	—	mA
Low Level Output Current	I _{OL}	V _{OL} =0.4V V _{IN} =V _{SS} , V _{DD}	5	1.4	—	1.1	—	—	0.8	—	mA
Input Voltage	"H" Level V _{IH}	I _{OUT} < 1μA V _{OUT} =0.5V	5	4.0	—	4.0	—	—	4.0	—	V
	"L" Level V _{IL}	V _{OUT} =4.5V	5	—	1.0	—	—	1.0	—	1.0	V
Input Current	"H" Level I _{IH}	V _{IH} =8.0V	8	—	0.3	—	10 ⁻⁵	0.3	—	1.0	μA
	"L" Level I _{IL}	V _{IL} =0.0V	8	—	-0.3	—	-10 ⁻⁵	-0.3	—	-1.0	μA
Quiescent Supply Current	I _{DD}	*V _{IN} =V _{SS} , V _{DD}	5	—	12.5	—	10 ⁻³	12.5	—	75	μA

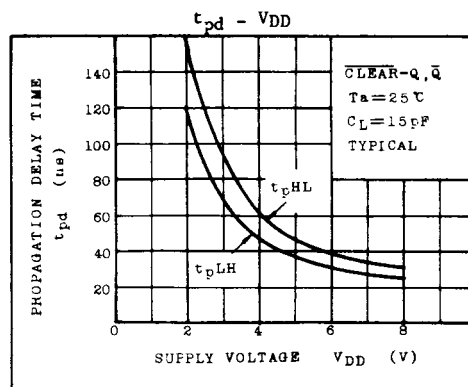
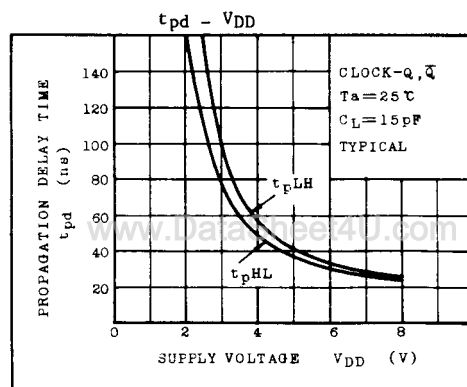
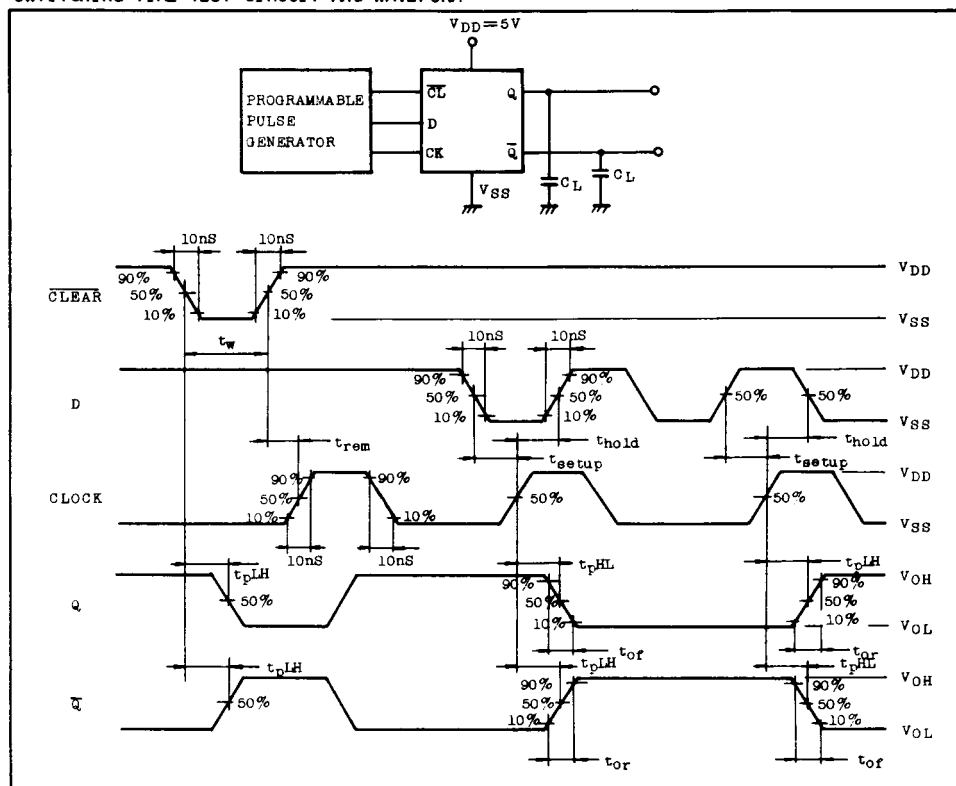
*All valid input combinations.

SWITCHING CHARACTERISTICS (T_a=25°C, V_{SS}=0.0V, C_L=15pF)

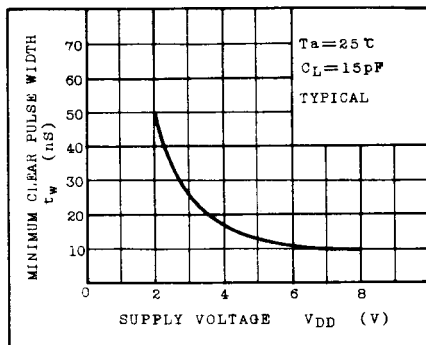
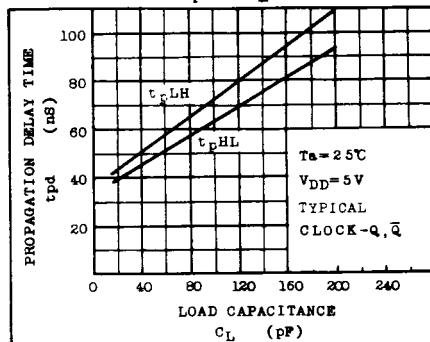
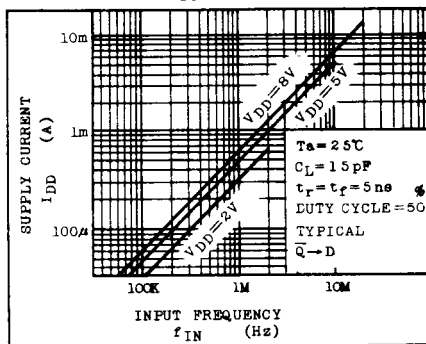
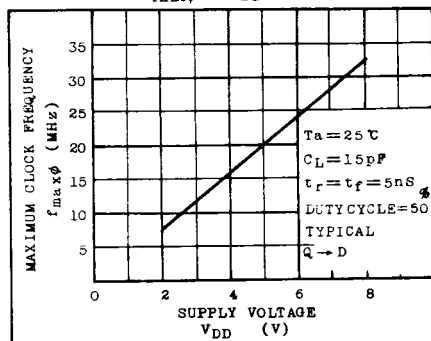
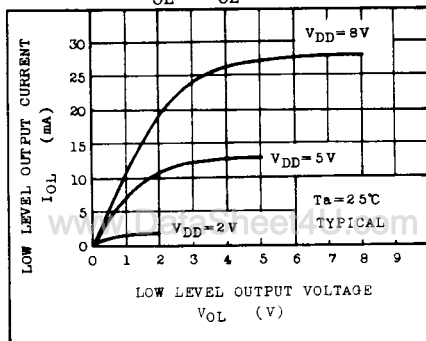
CHARACTERISTIC	SYMBOL	TEST CONDITION	V _{DD}	MIN.	TYP.	MAX.	UNIT
Output Rise Time	t _{or}	CLOCK - Q, $\overline{Q}$	5	—	18	35	ns
Output Fall Time	t _{of}		5	—	17	30	ns
Propagation Delay Time	(Low-High)	CLOCK - Q, $\overline{Q}$	5	—	42	63	ns
	(High-Low)		5	—	38	57	
	(Low-High)	$\overline{\text{CLEAR}}$ - Q, $\overline{Q}$	5	—	35	53	
	(High-Low)		5	—	45	68	
Min. Width of Pulse	t _w	$\overline{\text{CLEAR}}$	5	—	13	24	ns
Max. Clock Rise Time	t _{r0}	D-CLOCK	5	1.0	7.0	—	μs
Max. Clock Fall Time	t _{f0}		5	—	—	—	μs
Min. Data Hold Time	t _{hold}	D-CLOCK	5	—	—	5	ns
Min. Data Setup Time	t _{set-up}		5	—	—	25	ns
Input Capacitance	C _{IN}		5	—	5	—	pF
Max. Clock Frequency	f _{MAX}		5	10	20	—	MHz
Min. Clear Removal Time	t _{rem}		5	—	17	25	ns

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SWITCHING TIME TEST CIRCUIT AND WAVEFORM



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 $t_w - V_{DD}$  $t_{pd} - C_L$  $I_{DD} - f_{IN}$  $f_{MAX\phi} - V_{DD}$  $I_{OL} - V_{OL}$  $I_{OH} - (V_{DD} - V_{OH})$ 